

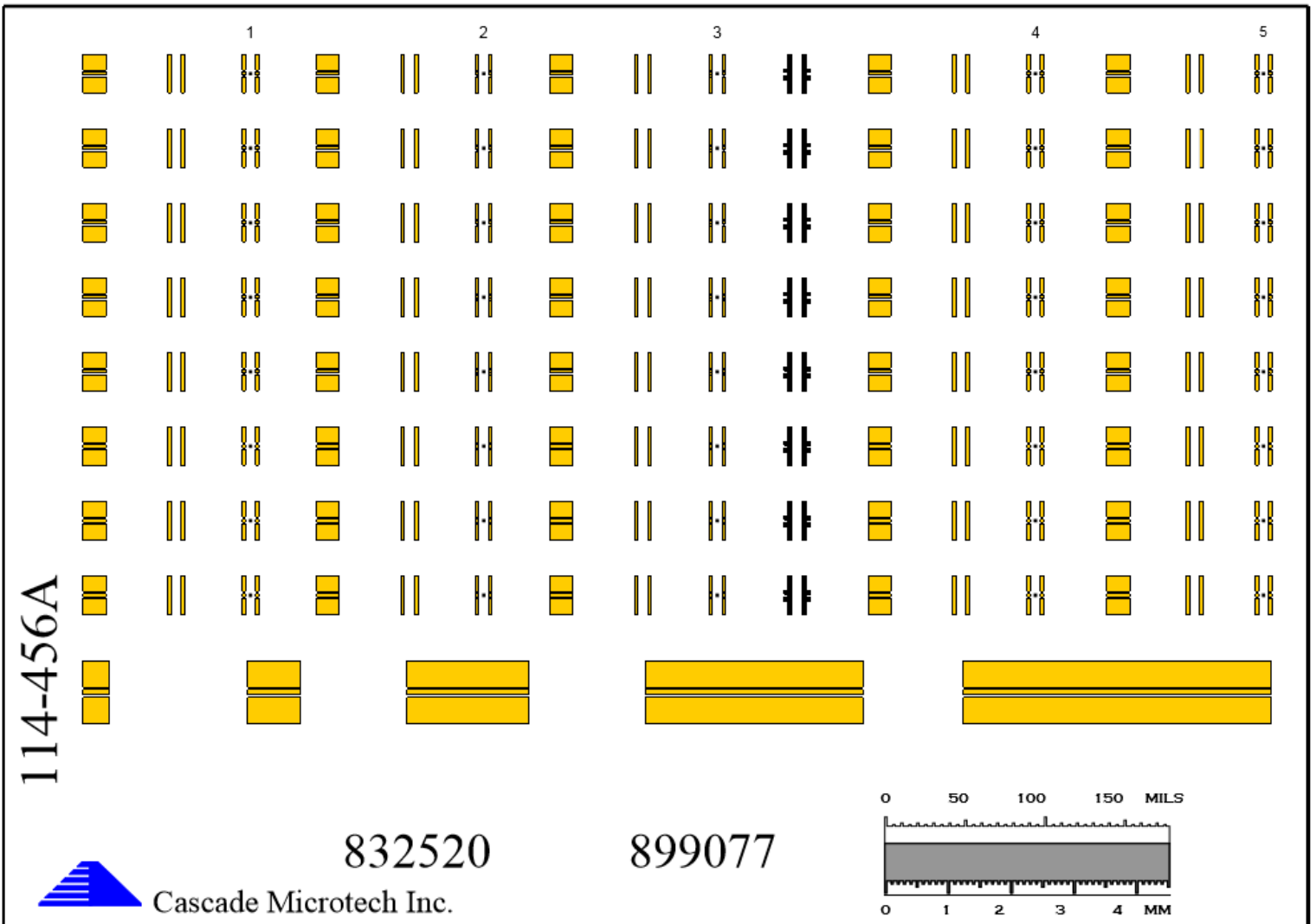
# Cascade Impedance Standard Substrate Map

000111100010

> **P/N: 114-456**

Pitch: 100  $\mu\text{m}$  - 150  $\mu\text{m}$


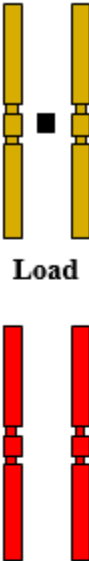
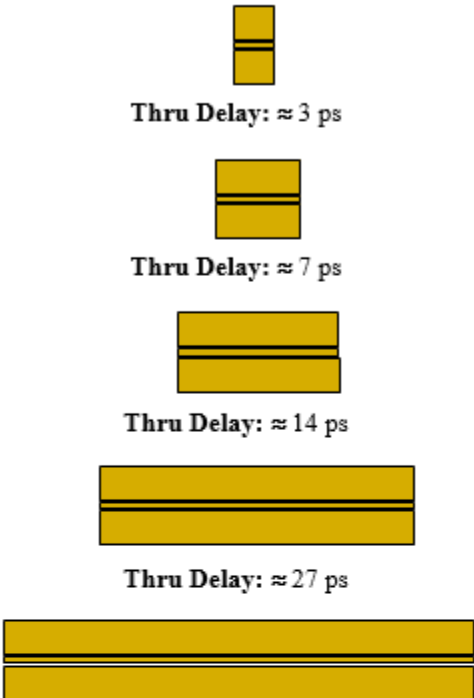

Configuration: **GSG**



## > Key to Map

### Key to the 114-456 Map

Substrate specifications: Material: Alumina; Thickness: 25 mils (635  $\mu\text{m}$ ); Dielectric constant: 9.9

 <p><b>Thru</b></p> <p><b>Short</b></p>	<p><b>Thru delay:</b> 2 ps</p> <p><b>Impedance:</b> Nominally 50 <math>\Omega</math></p> <p><b>Recommended Overtravel:</b></p> <p>ACP 75 – 125 <math>\mu\text{m}</math></p> <p>Infinity 50 – 75 <math>\mu\text{m}</math></p>	 <p><b>Load</b></p> <p><b>Precision 50 <math>\Omega</math> Load</b></p>	<p>For optimum calibration accuracy <b>only the Red -marked load standards</b> should be used</p> <p><b>DC accuracy:</b> +/- 0.3 %</p> <p><b>Note:</b> Ensure the bias supply is turned <b>off</b> during calibration. Applying bias to the probe during calibration could cause the resistance of the load to change</p>	<p><b>Verification Lines</b></p>  <p><b>Thru Delay:</b> <math>\approx</math> 3 ps</p> <p><b>Thru Delay:</b> <math>\approx</math> 7 ps</p> <p><b>Thru Delay:</b> <math>\approx</math> 14 ps</p> <p><b>Thru Delay:</b> <math>\approx</math> 27 ps</p> <p><b>Thru Delay:</b> <math>\approx</math> 40 ps</p>	 <p><b>A-H</b></p> <p><b>Alignment Marks</b></p> <p><b>Note:</b> An <b>Open</b> is synthesized by raising the probes in air a minimum distance of 250 <math>\mu\text{m}</math> above the chuck surface</p>
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All of the above specifications are based on an overtravel (downward movement of probe after initial touchdown on the substrate) of 50-75  $\mu\text{m}$ . This amount of overtravel can be set before calibration on the Impedance Standard Substrate (ISS) using the alignment marks (allows precise setting of probe separation and overtravel). Figure 1 shows that initial contact with the edge of the probe tips should be made at reference plane X. The desired overtravel and thus skate (forward movement of probe tips after initial contact with substrate) is then achieved by adjusting the Z height on the positioner to move the edge of the probe tips to reference plane Y. This can also be seen from the photographic images shown in Figure 2.

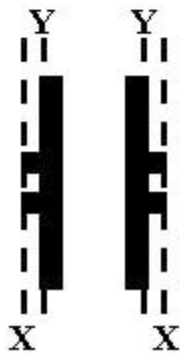


Figure 1: Alignment Marks

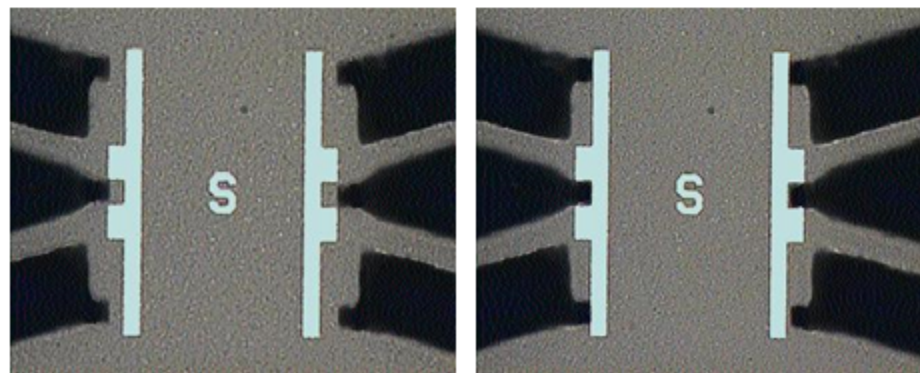


Figure 2: Images showing correct alignment and placement of probe tips

**Calibration Coefficients** are dependent on the probe tip configuration, placement on a standard, and the standard configurations. This leads to unique calibration coefficients for a unique pair of probe and ISS. Therefore, the calibration coefficients are supplied with the probe not with the ISS.